

JEOL 2010F Driver's test

1. Unloading of single tilt specimen holder from TEM (stage neutralized before extraction; follows proper sequence to avoid vacuum crash).
2. Loading of specimen into specimen holder (proper securing of specimen)
3. Loading of holder into TEM (follows proper sequence to avoid vacuum crash)
4. Opening of column valves (appropriate vacuum level reached)
5. Completion of basic alignment of instrument (C2 aperture, gun tilt, condenser astigmatism, eucentric height set at DV +0, alpha selector setting = 1 for HR imaging, deflector coil balancing, current centering)
6. Select and center correct objective aperture for high-resolution imaging in DIFF mode
7. Collect properly focused (slight under focus) and exposed high-resolution image at ~200 k \times with the digital camera in both "view" and "acquire" modes; correction of objective lens astigmatism (if needed)
8. Collect properly focused (slight under focus) and exposed BF image at ~25 k \times (alpha selector = 3 and appropriate objective aperture size) with the digital camera in both "view" and "acquire" modes
9. Collect diffraction pattern with the digital camera (appropriate procedure used for type of specimen being analyzed)
10. Proper finishing of session (magnification set to 100 k \times , SPOT SIZE = 1, alpha selector = 3, set DV +0, neutralize stage, retraction of objective/SA apertures, close column valves)
11. Unloading of specimen holder from TEM (stage neutralized before extraction; follows proper sequence to avoid vacuum crash)
12. Unloading of specimen from specimen holder
13. Loading of single tilt holder into TEM (follows proper sequence to avoid vacuum crash); returning of double tilt holder to plasma clean (if needed)